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### Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	359200
Number of Logic Elements/Cells	952000
Total RAM Bits	53248000
Number of I/O	840
Number of Gates	-
Voltage - Supply	0.82V ~ 0.88V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1932-BBGA, FCBGA
Supplier Device Package	1932-FBGA, FC (45x45)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/intel/5sgxeabn3f45c4n">https://www.e-xfl.com/product-detail/intel/5sgxeabn3f45c4n</a>

## Recommended Operating Conditions

This section lists the functional operating limits for the AC and DC parameters for Stratix V devices. Table 6 lists the steady-state voltage and current values expected from Stratix V devices. Power supply ramps must all be strictly monotonic, without plateaus.

**Table 6. Recommended Operating Conditions for Stratix V Devices (Part 1 of 2)**

Symbol	Description	Condition	Min <sup>(4)</sup>	Typ	Max <sup>(4)</sup>	Unit
V <sub>CC</sub>	Core voltage and periphery circuitry power supply (C1, C2, I2, and I3YY speed grades)	—	0.87	0.9	0.93	V
	Core voltage and periphery circuitry power supply (C2L, C3, C4, I2L, I3, I3L, and I4 speed grades) <sup>(3)</sup>	—	0.82	0.85	0.88	V
V <sub>CCPT</sub>	Power supply for programmable power technology	—	1.45	1.50	1.55	V
V <sub>CC_AUX</sub>	Auxiliary supply for the programmable power technology	—	2.375	2.5	2.625	V
V <sub>CCPD</sub> <sup>(1)</sup>	I/O pre-driver (3.0 V) power supply	—	2.85	3.0	3.15	V
	I/O pre-driver (2.5 V) power supply	—	2.375	2.5	2.625	V
V <sub>CCIO</sub>	I/O buffers (3.0 V) power supply	—	2.85	3.0	3.15	V
	I/O buffers (2.5 V) power supply	—	2.375	2.5	2.625	V
	I/O buffers (1.8 V) power supply	—	1.71	1.8	1.89	V
	I/O buffers (1.5 V) power supply	—	1.425	1.5	1.575	V
	I/O buffers (1.35 V) power supply	—	1.283	1.35	1.45	V
	I/O buffers (1.25 V) power supply	—	1.19	1.25	1.31	V
	I/O buffers (1.2 V) power supply	—	1.14	1.2	1.26	V
V <sub>CCPGM</sub>	Configuration pins (3.0 V) power supply	—	2.85	3.0	3.15	V
	Configuration pins (2.5 V) power supply	—	2.375	2.5	2.625	V
	Configuration pins (1.8 V) power supply	—	1.71	1.8	1.89	V
V <sub>CCA_FPLL</sub>	PLL analog voltage regulator power supply	—	2.375	2.5	2.625	V
V <sub>CCD_FPLL</sub>	PLL digital voltage regulator power supply	—	1.45	1.5	1.55	V
V <sub>CCBAT</sub> <sup>(2)</sup>	Battery back-up power supply (For design security volatile key register)	—	1.2	—	3.0	V
V <sub>I</sub>	DC input voltage	—	−0.5	—	3.6	V
V <sub>O</sub>	Output voltage	—	0	—	V <sub>CCIO</sub>	V
T <sub>J</sub>	Operating junction temperature	Commercial	0	—	85	°C
		Industrial	−40	—	100	°C

**Table 13. OCT Variation after Power-Up Calibration for Stratix V Devices (Part 2 of 2) <sup>(1)</sup>**

Symbol	Description	V <sub>CCIO</sub> (V)	Typical	Unit
dR/dT	OCT variation with temperature without recalibration	3.0	0.189	%/ <sup>o</sup> C
		2.5	0.208	
		1.8	0.266	
		1.5	0.273	
		1.2	0.317	

**Note to Table 13:**

(1) Valid for a V<sub>CCIO</sub> range of  $\pm 5\%$  and a temperature range of 0° to 85°C.

**Pin Capacitance**

Table 14 lists the Stratix V device family pin capacitance.

**Table 14. Pin Capacitance for Stratix V Devices**

Symbol	Description	Value	Unit
C <sub>IOTB</sub>	Input capacitance on the top and bottom I/O pins	6	pF
C <sub>IOLR</sub>	Input capacitance on the left and right I/O pins	6	pF
C <sub>OUTFB</sub>	Input capacitance on dual-purpose clock output and feedback pins	6	pF

**Hot Socketing**

Table 15 lists the hot socketing specifications for Stratix V devices.

**Table 15. Hot Socketing Specifications for Stratix V Devices**

Symbol	Description	Maximum
I <sub>IOPIN</sub> (DC)	DC current per I/O pin	300 $\mu$ A
I <sub>IOPIN</sub> (AC)	AC current per I/O pin	8 mA <sup>(1)</sup>
I <sub>XCVR-TX</sub> (DC)	DC current per transceiver transmitter pin	100 mA
I <sub>XCVR-RX</sub> (DC)	DC current per transceiver receiver pin	50 mA

**Note to Table 15:**

(1) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns,  $|I_{IOPIN}| = C \, dv/dt$ , in which C is the I/O pin capacitance and dv/dt is the slew rate.

## Internal Weak Pull-Up Resistor

Table 16 lists the weak pull-up resistor values for Stratix V devices.

**Table 16. Internal Weak Pull-Up Resistor for Stratix V Devices <sup>(1), (2)</sup>**

Symbol	Description	V <sub>CCIO</sub> Conditions (V) <sup>(3)</sup>	Value <sup>(4)</sup>	Unit
R <sub>PU</sub>	Value of the I/O pin pull-up resistor before and during configuration, as well as user mode if you enable the programmable pull-up resistor option.	3.0 ±5%	25	kΩ
		2.5 ±5%	25	kΩ
		1.8 ±5%	25	kΩ
		1.5 ±5%	25	kΩ
		1.35 ±5%	25	kΩ
		1.25 ±5%	25	kΩ
		1.2 ±5%	25	kΩ

### Notes to Table 16:

- (1) All I/O pins have an option to enable the weak pull-up resistor except the configuration, test, and JTAG pins.
- (2) The internal weak pull-down feature is only available for the JTAG TCK pin. The typical value for this internal weak pull-down resistor is approximately 25 kΩ.
- (3) The pin pull-up resistance values may be lower if an external source drives the pin higher than V<sub>CCIO</sub>.
- (4) These specifications are valid with a ±10% tolerance to cover changes over PVT.

## I/O Standard Specifications

Table 17 through Table 22 list the input voltage (V<sub>IH</sub> and V<sub>IL</sub>), output voltage (V<sub>OH</sub> and V<sub>OL</sub>), and current drive characteristics (I<sub>OH</sub> and I<sub>OL</sub>) for various I/O standards supported by Stratix V devices. These tables also show the Stratix V device family I/O standard specifications. The V<sub>OL</sub> and V<sub>OH</sub> values are valid at the corresponding I<sub>OH</sub> and I<sub>OL</sub>, respectively.

For an explanation of the terms used in Table 17 through Table 22, refer to “Glossary” on page 65. For tolerance calculations across all SSTL and HSTL I/O standards, refer to Altera knowledge base solution rd07262012\_486.

**Table 17. Single-Ended I/O Standards for Stratix V Devices**

I/O Standard	V <sub>CCIO</sub> (V)			V <sub>IL</sub> (V)		V <sub>IH</sub> (V)		V <sub>OL</sub> (V)	V <sub>OH</sub> (V)	I <sub>OL</sub> (mA)	I <sub>OH</sub> (mA)
	Min	Typ	Max	Min	Max	Min	Max	Max	Min		
LVTTTL	2.85	3	3.15	−0.3	0.8	1.7	3.6	0.4	2.4	2	−2
LVC MOS	2.85	3	3.15	−0.3	0.8	1.7	3.6	0.2	V <sub>CCIO</sub> − 0.2	0.1	−0.1
2.5 V	2.375	2.5	2.625	−0.3	0.7	1.7	3.6	0.4	2	1	−1
1.8 V	1.71	1.8	1.89	−0.3	0.35 * V <sub>CCIO</sub>	0.65 * V <sub>CCIO</sub>	V <sub>CCIO</sub> + 0.3	0.45	V <sub>CCIO</sub> − 0.45	2	−2
1.5 V	1.425	1.5	1.575	−0.3	0.35 * V <sub>CCIO</sub>	0.65 * V <sub>CCIO</sub>	V <sub>CCIO</sub> + 0.3	0.25 * V <sub>CCIO</sub>	0.75 * V <sub>CCIO</sub>	2	−2
1.2 V	1.14	1.2	1.26	−0.3	0.35 * V <sub>CCIO</sub>	0.65 * V <sub>CCIO</sub>	V <sub>CCIO</sub> + 0.3	0.25 * V <sub>CCIO</sub>	0.75 * V <sub>CCIO</sub>	2	−2

**Table 23. Transceiver Specifications for Stratix V GX and GS Devices <sup>(1)</sup> (Part 4 of 7)**

Symbol/ Description	Conditions	Transceiver Speed Grade 1			Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Differential on-chip termination resistors <sup>(21)</sup>	85- $\Omega$ setting	—	85 $\pm$ 30%	—	—	85 $\pm$ 30%	—	—	85 $\pm$ 30%	—	$\Omega$
	100- $\Omega$ setting	—	100 $\pm$ 30%	—	—	100 $\pm$ 30%	—	—	100 $\pm$ 30%	—	$\Omega$
	120- $\Omega$ setting	—	120 $\pm$ 30%	—	—	120 $\pm$ 30%	—	—	120 $\pm$ 30%	—	$\Omega$
	150- $\Omega$ setting	—	150 $\pm$ 30%	—	—	150 $\pm$ 30%	—	—	150 $\pm$ 30%	—	$\Omega$
$V_{ICM}$ (AC and DC coupled)	$V_{CCR\_GXB} = 0.85\text{ V}$ or 0.9 V full bandwidth	—	600	—	—	600	—	—	600	—	mV
	$V_{CCR\_GXB} = 0.85\text{ V}$ or 0.9 V half bandwidth	—	600	—	—	600	—	—	600	—	mV
	$V_{CCR\_GXB} = 1.0\text{ V}/1.05\text{ V}$ full bandwidth	—	700	—	—	700	—	—	700	—	mV
	$V_{CCR\_GXB} = 1.0\text{ V}$ half bandwidth	—	750	—	—	750	—	—	750	—	mV
$t_{LTR}$ <sup>(11)</sup>	—	—	—	10	—	—	10	—	—	10	$\mu\text{s}$
$t_{LTD}$ <sup>(12)</sup>	—	4	—	—	4	—	—	4	—	—	$\mu\text{s}$
$t_{LTD\_manual}$ <sup>(13)</sup>	—	4	—	—	4	—	—	4	—	—	$\mu\text{s}$
$t_{LTR\_LTD\_manual}$ <sup>(14)</sup>	—	15	—	—	15	—	—	15	—	—	$\mu\text{s}$
Run Length	—	—	—	200	—	—	200	—	—	200	UI
Programmable equalization (AC Gain) <sup>(10)</sup>	Full bandwidth (6.25 GHz) Half bandwidth (3.125 GHz)	—	—	16	—	—	16	—	—	16	dB

Table 26 shows the approximate maximum data rate using the 10G PCS.

**Table 26. Stratix V 10G PCS Approximate Maximum Data Rate <sup>(1)</sup>**

Mode <sup>(2)</sup>	Transceiver Speed Grade	PMA Width	64	40	40	40	32	32
		PCS Width	64	66/67	50	40	64/66/67	32
FIFO or Register	1	C1, C2, C2L, I2, I2L core speed grade	14.1	14.1	10.69	14.1	13.6	13.6
	2	C1, C2, C2L, I2, I2L core speed grade	12.5	12.5	10.69	12.5	12.5	12.5
		C3, I3, I3L core speed grade	12.5	12.5	10.69	12.5	10.88	10.88
	3	C1, C2, C2L, I2, I2L core speed grade	8.5 Gbps					
		C3, I3, I3L core speed grade						
		C4, I4 core speed grade						
		I3YY core speed grade	10.3125 Gbps					

**Notes to Table 26:**

- (1) The maximum data rate is in Gbps.
- (2) The Phase Compensation FIFO can be configured in FIFO mode or register mode. In the FIFO mode, the pointers are not fixed, and the latency can vary. In the register mode the pointers are fixed for low latency.

**Table 28. Transceiver Specifications for Stratix V GT Devices (Part 3 of 5) <sup>(1)</sup>**

Symbol/ Description	Conditions	Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	
Differential on-chip termination resistors <sup>(7)</sup>	GT channels	—	100	—	—	100	—	$\Omega$
Differential on-chip termination resistors for GX channels <sup>(19)</sup>	85- $\Omega$ setting	—	85 $\pm$ 30%	—	—	85 $\pm$ 30%	—	$\Omega$
	100- $\Omega$ setting	—	100 $\pm$ 30%	—	—	100 $\pm$ 30%	—	$\Omega$
	120- $\Omega$ setting	—	120 $\pm$ 30%	—	—	120 $\pm$ 30%	—	$\Omega$
	150- $\Omega$ setting	—	150 $\pm$ 30%	—	—	150 $\pm$ 30%	—	$\Omega$
V <sub>ICM</sub> (AC coupled)	GT channels	—	650	—	—	650	—	mV
VICM (AC and DC coupled) for GX Channels	VCCR_GXB = 0.85 V or 0.9 V	—	600	—	—	600	—	mV
	VCCR_GXB = 1.0 V full bandwidth	—	700	—	—	700	—	mV
	VCCR_GXB = 1.0 V half bandwidth	—	750	—	—	750	—	mV
t <sub>LTR</sub> <sup>(9)</sup>	—	—	—	10	—	—	10	$\mu$ s
t <sub>LTD</sub> <sup>(10)</sup>	—	4	—	—	4	—	—	$\mu$ s
t <sub>LTD_manual</sub> <sup>(11)</sup>	—	4	—	—	4	—	—	$\mu$ s
t <sub>LTR_LTD_manual</sub> <sup>(12)</sup>	—	15	—	—	15	—	—	$\mu$ s
Run Length	GT channels	—	—	72	—	—	72	CID
	GX channels	<sup>(8)</sup>						
CDR PPM	GT channels	—	—	1000	—	—	1000	$\pm$ PPM
	GX channels	<sup>(8)</sup>						
Programmable equalization (AC Gain) <sup>(5)</sup>	GT channels	—	—	14	—	—	14	dB
	GX channels	<sup>(8)</sup>						
Programmable DC gain <sup>(6)</sup>	GT channels	—	—	7.5	—	—	7.5	dB
	GX channels	<sup>(8)</sup>						
Differential on-chip termination resistors <sup>(7)</sup>	GT channels	—	100	—	—	100	—	$\Omega$
<b>Transmitter</b>								
Supported I/O Standards	—	1.4-V and 1.5-V PCML						
Data rate (Standard PCS)	GX channels	600	—	8500	600	—	8500	Mbps
Data rate (10G PCS)	GX channels	600	—	12,500	600	—	12,500	Mbps

- XFI
- ASI
- HiGig/HiGig+
- HiGig2/HiGig2+
- Serial Data Converter (SDC)
- GPON
- SDI
- SONET
- Fibre Channel (FC)
- PCIe
- QPI
- SFF-8431

Download the Stratix V Characterization Report Tool to view the characterization report summary for these protocols.

## Core Performance Specifications

This section describes the clock tree, phase-locked loop (PLL), digital signal processing (DSP), memory blocks, configuration, and JTAG specifications.

### Clock Tree Specifications

Table 30 lists the clock tree specifications for Stratix V devices.

**Table 30. Clock Tree Performance for Stratix V Devices <sup>(1)</sup>**

Symbol	Performance			Unit
	C1, C2, C2L, I2, and I2L	C3, I3, I3L, and I3YY	C4, I4	
Global and Regional Clock	717	650	580	MHz
Periphery Clock	550	500	500	MHz

**Note to Table 30:**

(1) The Stratix V ES devices are limited to 600 MHz core clock tree performance.



**Table 31. PLL Specifications for Stratix V Devices (Part 2 of 3)**

Symbol	Parameter	Min	Typ	Max	Unit
$t_{\text{INCCJ}}$ <sup>(3), (4)</sup>	Input clock cycle-to-cycle jitter ( $f_{\text{REF}} \geq 100$ MHz)	—	—	0.15	UI (p-p)
	Input clock cycle-to-cycle jitter ( $f_{\text{REF}} < 100$ MHz)	−750	—	+750	ps (p-p)
$t_{\text{OUTPJ\_DC}}$ <sup>(5)</sup>	Period Jitter for dedicated clock output ( $f_{\text{OUT}} \geq 100$ MHz)	—	—	175 <sup>(1)</sup>	ps (p-p)
	Period Jitter for dedicated clock output ( $f_{\text{OUT}} < 100$ MHz)	—	—	17.5 <sup>(1)</sup>	mUI (p-p)
$t_{\text{FOUTPJ\_DC}}$ <sup>(5)</sup>	Period Jitter for dedicated clock output in fractional PLL ( $f_{\text{OUT}} \geq 100$ MHz)	—	—	250 <sup>(11)</sup> , 175 <sup>(12)</sup>	ps (p-p)
	Period Jitter for dedicated clock output in fractional PLL ( $f_{\text{OUT}} < 100$ MHz)	—	—	25 <sup>(11)</sup> , 17.5 <sup>(12)</sup>	mUI (p-p)
$t_{\text{OUTCCJ\_DC}}$ <sup>(5)</sup>	Cycle-to-Cycle Jitter for a dedicated clock output ( $f_{\text{OUT}} \geq 100$ MHz)	—	—	175	ps (p-p)
	Cycle-to-Cycle Jitter for a dedicated clock output ( $f_{\text{OUT}} < 100$ MHz)	—	—	17.5	mUI (p-p)
$t_{\text{FOUTCCJ\_DC}}$ <sup>(5)</sup>	Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL ( $f_{\text{OUT}} \geq 100$ MHz)	—	—	250 <sup>(11)</sup> , 175 <sup>(12)</sup>	ps (p-p)
	Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL ( $f_{\text{OUT}} < 100$ MHz)+	—	—	25 <sup>(11)</sup> , 17.5 <sup>(12)</sup>	mUI (p-p)
$t_{\text{OUTPJ\_IO}}$ <sup>(5), (8)</sup>	Period Jitter for a clock output on a regular I/O in integer PLL ( $f_{\text{OUT}} \geq 100$ MHz)	—	—	600	ps (p-p)
	Period Jitter for a clock output on a regular I/O ( $f_{\text{OUT}} < 100$ MHz)	—	—	60	mUI (p-p)
$t_{\text{FOUTPJ\_IO}}$ <sup>(5), (8), (11)</sup>	Period Jitter for a clock output on a regular I/O in fractional PLL ( $f_{\text{OUT}} \geq 100$ MHz)	—	—	600 <sup>(10)</sup>	ps (p-p)
	Period Jitter for a clock output on a regular I/O in fractional PLL ( $f_{\text{OUT}} < 100$ MHz)	—	—	60 <sup>(10)</sup>	mUI (p-p)
$t_{\text{OUTCCJ\_IO}}$ <sup>(5), (8)</sup>	Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL ( $f_{\text{OUT}} \geq 100$ MHz)	—	—	600	ps (p-p)
	Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL ( $f_{\text{OUT}} < 100$ MHz)	—	—	60 <sup>(10)</sup>	mUI (p-p)
$t_{\text{FOUTCCJ\_IO}}$ <sup>(5), (8), (11)</sup>	Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL ( $f_{\text{OUT}} \geq 100$ MHz)	—	—	600 <sup>(10)</sup>	ps (p-p)
	Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL ( $f_{\text{OUT}} < 100$ MHz)	—	—	60	mUI (p-p)
$t_{\text{CASC\_OUTPJ\_DC}}$ <sup>(5), (6)</sup>	Period Jitter for a dedicated clock output in cascaded PLLs ( $f_{\text{OUT}} \geq 100$ MHz)	—	—	175	ps (p-p)
	Period Jitter for a dedicated clock output in cascaded PLLs ( $f_{\text{OUT}} < 100$ MHz)	—	—	17.5	mUI (p-p)
$f_{\text{DRIFT}}$	Frequency drift after PFDENA is disabled for a duration of 100 $\mu$ s	—	—	$\pm 10$	%
$dK_{\text{BIT}}$	Bit number of Delta Sigma Modulator (DSM)	8	24	32	Bits
$K_{\text{VALUE}}$	Numerator of Fraction	128	8388608	2147483648	—

**Table 31. PLL Specifications for Stratix V Devices (Part 3 of 3)**

Symbol	Parameter	Min	Typ	Max	Unit
$f_{RES}$	Resolution of VCO frequency ( $f_{INPFD} = 100$ MHz)	390625	5.96	0.023	Hz

**Notes to Table 31:**

- (1) This specification is limited in the Quartus II software by the I/O maximum frequency. The maximum I/O frequency is different for each I/O standard.
- (2) This specification is limited by the lower of the two: I/O  $f_{MAX}$  or  $f_{OUT}$  of the PLL.
- (3) A high input jitter directly affects the PLL output jitter. To have low PLL output clock jitter, you must provide a clean clock source < 120 ps.
- (4)  $f_{REF}$  is  $f_{IN}/N$  when  $N = 1$ .
- (5) Peak-to-peak jitter with a probability level of  $10^{-12}$  (14 sigma, 99.9999999974404% confidence level). The output jitter specification applies to the intrinsic jitter of the PLL, when an input jitter of 30 ps is applied. The external memory interface clock output jitter specifications use a different measurement method and are available in Table 44 on page 52.
- (6) The cascaded PLL specification is only applicable with the following condition:
  - a. Upstream PLL:  $0.59\text{MHz} \leq \text{Upstream PLL BW} < 1$  MHz
  - b. Downstream PLL: Downstream PLL BW > 2 MHz
- (7) High bandwidth PLL settings are not supported in external feedback mode.
- (8) The external memory interface clock output jitter specifications use a different measurement method, which is available in Table 42 on page 50.
- (9) The VCO frequency reported by the Quartus II software in the PLL Usage Summary section of the compilation report takes into consideration the VCO post-scale counter K value. Therefore, if the counter K has a value of 2, the frequency reported can be lower than the  $f_{VCO}$  specification.
- (10) This specification only covers fractional PLL for low bandwidth. The  $f_{VCO}$  for fractional value range 0.05 - 0.95 must be  $\geq 1000$  MHz, while  $f_{VCO}$  for fractional value range 0.20 - 0.80 must be  $\geq 1200$  MHz.
- (11) This specification only covered fractional PLL for low bandwidth. The  $f_{VCO}$  for fractional value range 0.05-0.95 must be  $\geq 1000$  MHz.
- (12) This specification only covered fractional PLL for low bandwidth. The  $f_{VCO}$  for fractional value range 0.20-0.80 must be  $\geq 1200$  MHz.

## DSP Block Specifications

Table 32 lists the Stratix V DSP block performance specifications.

**Table 32. Block Performance Specifications for Stratix V DSP Devices (Part 1 of 2)**

Mode	Peformance							Unit
	C1	C2, C2L	I2, I2L	C3	I3, I3L, I3YY	C4	I4	
Modes using one DSP								
Three 9 x 9	600	600	600	480	480	420	420	MHz
One 18 x 18	600	600	600	480	480	420	400	MHz
Two partial 18 x 18 (or 16 x 16)	600	600	600	480	480	420	400	MHz
One 27 x 27	500	500	500	400	400	350	350	MHz
One 36 x 18	500	500	500	400	400	350	350	MHz
One sum of two 18 x 18(One sum of 2 16 x 16)	500	500	500	400	400	350	350	MHz
One sum of square	500	500	500	400	400	350	350	MHz
One 18 x 18 plus 36 (a x b) + c	500	500	500	400	400	350	350	MHz
Modes using two DSPs								
Three 18 x 18	500	500	500	400	400	350	350	MHz
One sum of four 18 x 18	475	475	475	380	380	300	300	MHz
One sum of two 27 x 27	465	465	450	380	380	300	290	MHz
One sum of two 36 x 18	475	475	475	380	380	300	300	MHz
One complex 18 x 18	500	500	500	400	400	350	350	MHz
One 36 x 36	475	475	475	380	380	300	300	MHz

## Periphery Performance

This section describes periphery performance, including high-speed I/O and external memory interface.

I/O performance supports several system interfaces, such as the **LVDS** high-speed I/O interface, external memory interface, and the **PCI/PCI-X** bus interface.

General-purpose I/O standards such as 3.3-, 2.5-, 1.8-, and 1.5-**LVTTL/LVCMOS** are capable of a typical 167 MHz and 1.2-**LVCMOS** at 100 MHz interfacing frequency with a 10 pF load.



The actual achievable frequency depends on design- and system-specific factors. Ensure proper timing closure in your design and perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

### High-Speed I/O Specification

Table 36 lists high-speed I/O timing for Stratix V devices.

**Table 36. High-Speed I/O Specifications for Stratix V Devices <sup>(1)</sup>, <sup>(2)</sup> (Part 1 of 4)**

Symbol	Conditions	C1			C2, C2L, I2, I2L			C3, I3, I3L, I3YY			C4,I4			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
$f_{\text{HCLK\_in}}$ (input clock frequency) True Differential I/O Standards	Clock boost factor $W = 1$ to 40 <sup>(4)</sup>	5	—	800	5	—	800	5	—	625	5	—	525	MHz
$f_{\text{HCLK\_in}}$ (input clock frequency) Single Ended I/O Standards <sup>(3)</sup>	Clock boost factor $W = 1$ to 40 <sup>(4)</sup>	5	—	800	5	—	800	5	—	625	5	—	525	MHz
$f_{\text{HCLK\_in}}$ (input clock frequency) Single Ended I/O Standards	Clock boost factor $W = 1$ to 40 <sup>(4)</sup>	5	—	520	5	—	520	5	—	420	5	—	420	MHz
$f_{\text{HCLK\_OUT}}$ (output clock frequency)	—	5	—	800	5	—	800	5	—	625 <sup>(5)</sup>	5	—	525 <sup>(5)</sup>	MHz

**Table 36. High-Speed I/O Specifications for Stratix V Devices <sup>(1)</sup>, <sup>(2)</sup> (Part 2 of 4)**

Symbol	Conditions	C1			C2, C2L, I2, I2L			C3, I3, I3L, I3YY			C4,I4			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Transmitter														
True Differential I/O Standards - f <sub>HSDR</sub> (data rate)	SERDES factor J = 3 to 10 <sup>(9), (11), (12), (13), (14), (15), (16)</sup>	(6)	—	1600	(6)	—	1434	(6)	—	1250	(6)	—	1050	Mbps
	SERDES factor J ≥ 4  LVDS TX with DPA <sup>(12), (14), (15), (16)</sup>	(6)	—	1600	(6)	—	1600	(6)	—	1600	(6)	—	1250	Mbps
	SERDES factor J = 2, uses DDR Registers	(6)	—	(7)	(6)	—	(7)	(6)	—	(7)	(6)	—	(7)	Mbps
	SERDES factor J = 1, uses SDR Register	(6)	—	(7)	(6)	—	(7)	(6)	—	(7)	(6)	—	(7)	Mbps
Emulated Differential I/O Standards with Three External Output Resistor Networks - f <sub>HSDR</sub> (data rate) <sup>(10)</sup>	SERDES factor J = 4 to 10 <sup>(17)</sup>	(6)	—	1100	(6)	—	1100	(6)	—	840	(6)	—	840	Mbps
t <sub>x Jitter</sub> - True Differential I/O Standards	Total Jitter for Data Rate 600 Mbps - 1.25 Gbps	—	—	160	—	—	160	—	—	160	—	—	160	ps
	Total Jitter for Data Rate < 600 Mbps	—	—	0.1	—	—	0.1	—	—	0.1	—	—	0.1	UI
t <sub>x Jitter</sub> - Emulated Differential I/O Standards with Three External Output Resistor Network	Total Jitter for Data Rate 600 Mbps - 1.25 Gbps	—	—	300	—	—	300	—	—	300	—	—	325	ps
	Total Jitter for Data Rate < 600 Mbps	—	—	0.2	—	—	0.2	—	—	0.2	—	—	0.25	UI

Figure 7 shows the dynamic phase alignment (DPA) lock time specifications with the DPA PLL calibration option enabled.

**Figure 7. DPA Lock Time Specification with DPA PLL Calibration Enabled**

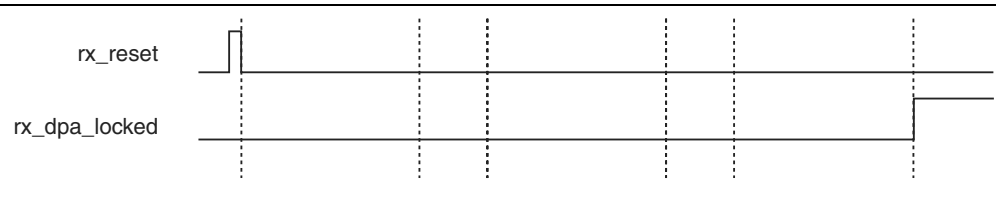


Table 37 lists the DPA lock time specifications for Stratix V devices.

**Table 37. DPA Lock Time Specifications for Stratix V GX Devices Only <sup>(1), (2), (3)</sup>**

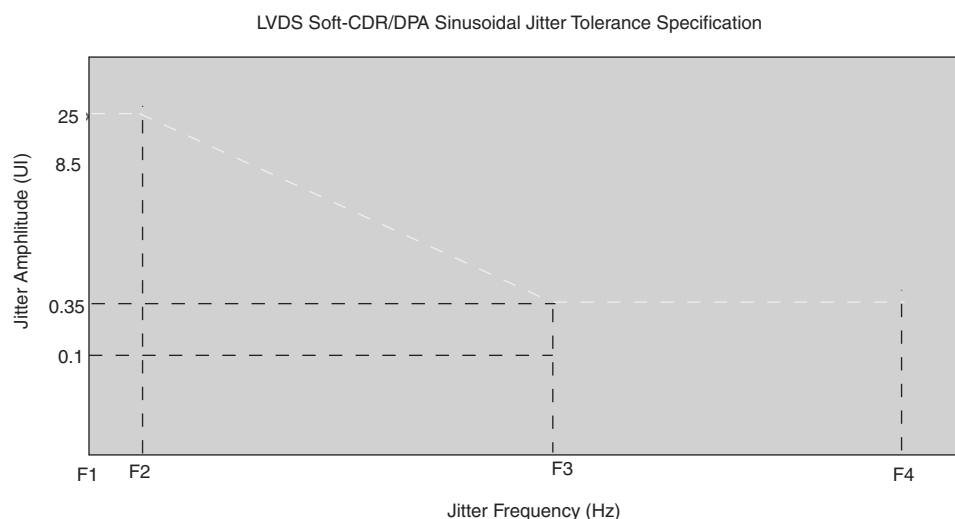
Standard	Training Pattern	Number of Data Transitions in One Repetition of the Training Pattern	Number of Repetitions per 256 Data Transitions <sup>(4)</sup>	Maximum
SPI-4	00000000001111111111	2	128	640 data transitions
Parallel Rapid I/O	00001111	2	128	640 data transitions
	10010000	4	64	640 data transitions
Miscellaneous	10101010	8	32	640 data transitions
	01010101	8	32	640 data transitions

**Notes to Table 37:**

- (1) The DPA lock time is for one channel.
- (2) One data transition is defined as a 0-to-1 or 1-to-0 transition.
- (3) The DPA lock time stated in this table applies to both commercial and industrial grade.
- (4) This is the number of repetitions for the stated training pattern to achieve the 256 data transitions.

Figure 8 shows the LVDS soft-clock data recovery (CDR)/DPA sinusoidal jitter tolerance specification for a data rate  $\geq 1.25$  Gbps. Table 38 lists the LVDS soft-CDR/DPA sinusoidal jitter tolerance specification for a data rate  $\geq 1.25$  Gbps.

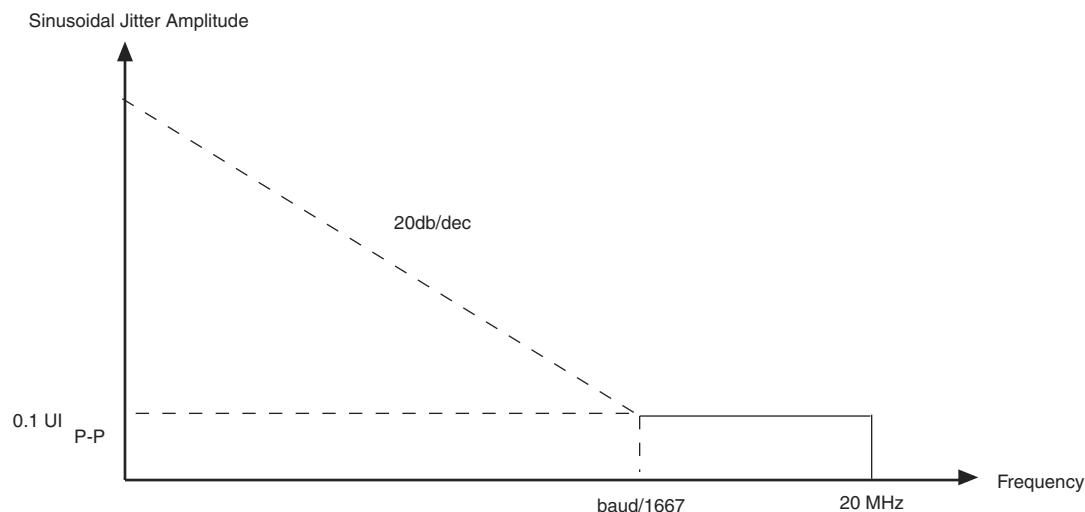
**Figure 8. LVDS Soft-CDR/DPA Sinusoidal Jitter Tolerance Specification for a Data Rate  $\geq 1.25$  Gbps**



**Table 38. LVDS Soft-CDR/DPA Sinusoidal Jitter Mask Values for a Data Rate  $\geq 1.25$  Gbps**

Jitter Frequency (Hz)		Sinusoidal Jitter (UI)
F1	10,000	25.000
F2	17,565	25.000
F3	1,493,000	0.350
F4	50,000,000	0.350

Figure 9 shows the LVDS soft-CDR/DPA sinusoidal jitter tolerance specification for a data rate  $< 1.25$  Gbps.

**Figure 9. LVDS Soft-CDR/DPA Sinusoidal Jitter Tolerance Specification for a Data Rate  $< 1.25$  Gbps**

### DLL Range, DQS Logic Block, and Memory Output Clock Jitter Specifications

Table 39 lists the DLL range specification for Stratix V devices. The DLL is always in 8-tap mode in Stratix V devices.

**Table 39. DLL Range Specifications for Stratix V Devices <sup>(1)</sup>**

C1	C2, C2L, I2, I2L	C3, I3, I3L, I3YY	C4,I4	Unit
300-933	300-933	300-890	300-890	MHz

**Note to Table 39:**

- (1) Stratix V devices support memory interface frequencies lower than 300 MHz, although the reference clock that feeds the DLL must be at least 300 MHz. To support interfaces below 300 MHz, multiply the reference clock feeding the DLL to ensure the frequency is within the supported range of the DLL.

Table 40 lists the DQS phase offset delay per stage for Stratix V devices.

**Table 40. DQS Phase Offset Delay Per Setting for Stratix V Devices <sup>(1), (2)</sup> (Part 1 of 2)**

Speed Grade	Min	Max	Unit
C1	8	14	ps
C2, C2L, I2, I2L	8	14	ps
C3,I3, I3L, I3YY	8	15	ps

**Table 42. Memory Output Clock Jitter Specification for Stratix V Devices <sup>(1)</sup>, (Part 2 of 2) <sup>(2)</sup>, <sup>(3)</sup>**

Clock Network	Parameter	Symbol	C1		C2, C2L, I2, I2L		C3, I3, I3L, I3YY		C4,I4		Unit
			Min	Max	Min	Max	Min	Max	Min	Max	
PHY Clock	Clock period jitter	$t_{JIT(per)}$	-25	25	-25	25	-30	30	-35	35	ps
	Cycle-to-cycle period jitter	$t_{JIT(cc)}$	-50	50	-50	50	-60	60	-70	70	ps
	Duty cycle jitter	$t_{JIT(duty)}$	-37.5	37.5	-37.5	37.5	-45	45	-56	56	ps

**Notes to Table 42:**

- (1) The clock jitter specification applies to the memory output clock pins generated using differential signal-splitter and DDIO circuits clocked by a PLL output routed on a PHY, regional, or global clock network as specified. Altera recommends using PHY clock networks whenever possible.
- (2) The clock jitter specification applies to the memory output clock pins clocked by an integer PLL.
- (3) The memory output clock jitter is applicable when an input jitter of 30 ps peak-to-peak is applied with bit error rate (BER) -12, equivalent to 14 sigma.

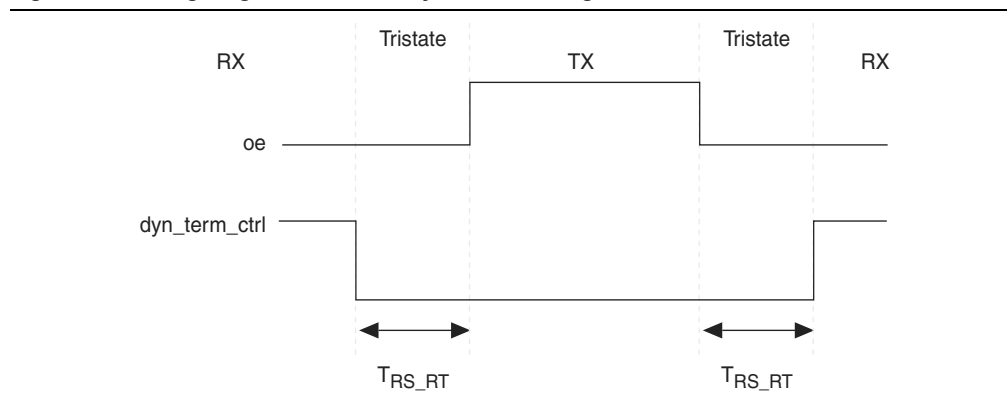
**OCT Calibration Block Specifications**

Table 43 lists the OCT calibration block specifications for Stratix V devices.

**Table 43. OCT Calibration Block Specifications for Stratix V Devices**

Symbol	Description	Min	Typ	Max	Unit
OCTUSRCLK	Clock required by the OCT calibration blocks	—	—	20	MHz
$T_{OCTCAL}$	Number of OCTUSRCLK clock cycles required for OCT $R_S/R_T$ calibration	—	1000	—	Cycles
$T_{OCTSHIFT}$	Number of OCTUSRCLK clock cycles required for the OCT code to shift out	—	32	—	Cycles
$T_{RS\_RT}$	Time required between the <code>dyn_term_ctrl</code> and <code>oe</code> signal transitions in a bidirectional I/O buffer to dynamically switch between OCT $R_S$ and $R_T$ (Figure 10)	—	2.5	—	ns

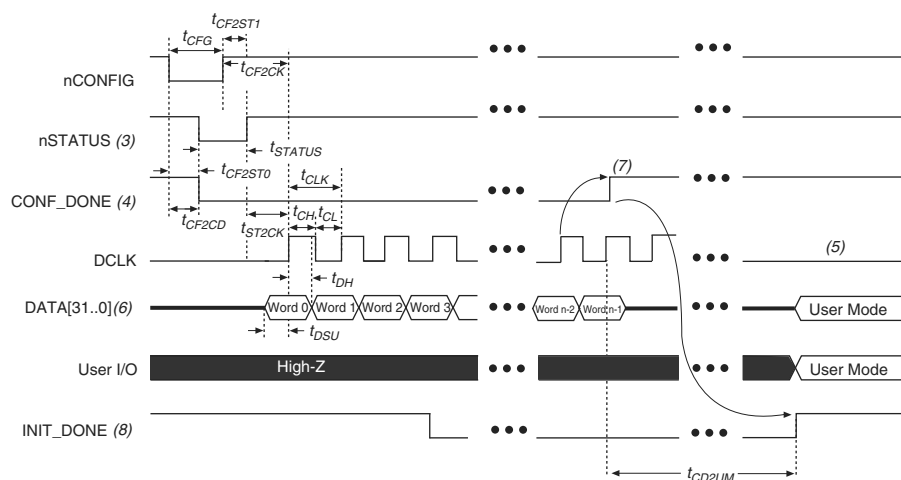
Figure 10 shows the timing diagram for the `oe` and `dyn_term_ctrl` signals.

**Figure 10. Timing Diagram for `oe` and `dyn_term_ctrl` Signals**

## FPP Configuration Timing when DCLK-to-DATA [] = 1

Figure 12 shows the timing waveform for FPP configuration when using a MAX II or MAX V device as an external host. This waveform shows timing when the DCLK-to-DATA [] ratio is 1.

**Figure 12. FPP Configuration Timing Waveform When the DCLK-to-DATA[] Ratio is 1 <sup>(1), (2)</sup>**



### Notes to Figure 12:

- (1) Use this timing waveform when the DCLK-to-DATA [] ratio is 1.
- (2) The beginning of this waveform shows the device in user mode. In user mode, nCONFIG, nSTATUS, and CONF\_DONE are at logic-high levels. When nCONFIG is pulled low, a reconfiguration cycle begins.
- (3) After power-up, the Stratix V device holds nSTATUS low for the time of the POR delay.
- (4) After power-up, before and during configuration, CONF\_DONE is low.
- (5) Do not leave DCLK floating after configuration. DCLK is ignored after configuration is complete. It can toggle high or low if required.
- (6) For FPP x16, use DATA [15..0]. For FPP x8, use DATA [7..0]. DATA [31..0] are available as a user I/O pin after configuration. The state of this pin depends on the dual-purpose pin settings.
- (7) To ensure a successful configuration, send the entire configuration data to the Stratix V device. CONF\_DONE is released high when the Stratix V device receives all the configuration data successfully. After CONF\_DONE goes high, send two additional falling edges on DCLK to begin initialization and enter user mode.
- (8) After the option bit to enable the INIT\_DONE pin is configured into the device, the INIT\_DONE goes low.



Table 50 lists the timing parameters for Stratix V devices for FPP configuration when the DCLK-to-DATA [] ratio is 1.

**Table 50. FPP Timing Parameters for Stratix V Devices <sup>(1)</sup>**

Symbol	Parameter	Minimum	Maximum	Units
t <sub>CF2CD</sub>	nCONFIG low to CONF_DONE low	—	600	ns
t <sub>CF2ST0</sub>	nCONFIG low to nSTATUS low	—	600	ns
t <sub>CFG</sub>	nCONFIG low pulse width	2	—	μs
t <sub>STATUS</sub>	nSTATUS low pulse width	268	1,506 <sup>(2)</sup>	μs
t <sub>CF2ST1</sub>	nCONFIG high to nSTATUS high	—	1,506 <sup>(3)</sup>	μs
t <sub>CF2CK</sub> <sup>(6)</sup>	nCONFIG high to first rising edge on DCLK	1,506	—	μs
t <sub>ST2CK</sub> <sup>(6)</sup>	nSTATUS high to first rising edge of DCLK	2	—	μs
t <sub>DSU</sub>	DATA [] setup time before rising edge on DCLK	5.5	—	ns
t <sub>DH</sub>	DATA [] hold time after rising edge on DCLK	0	—	ns
t <sub>CH</sub>	DCLK high time	$0.45 \times 1/f_{\text{MAX}}$	—	s
t <sub>CL</sub>	DCLK low time	$0.45 \times 1/f_{\text{MAX}}$	—	s
t <sub>CLK</sub>	DCLK period	$1/f_{\text{MAX}}$	—	s
f <sub>MAX</sub>	DCLK frequency (FPP ×8/×16)	—	125	MHz
	DCLK frequency (FPP ×32)	—	100	MHz
t <sub>CD2UM</sub>	CONF_DONE high to user mode <sup>(4)</sup>	175	437	μs
t <sub>CD2CU</sub>	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	—	—
t <sub>CD2UMC</sub>	CONF_DONE high to user mode with CLKUSR option on	t <sub>CD2CU</sub> + (8576 × CLKUSR period) <sup>(5)</sup>	—	—

**Notes to Table 50:**

- (1) Use these timing parameters when the decompression and design security features are disabled.
- (2) This value is applicable if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.
- (3) This value is applicable if you do not delay configuration by externally holding the nSTATUS low.
- (4) The minimum and maximum numbers apply only if you chose the internal oscillator as the clock source for initializing the device.
- (5) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the Initialization section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices” chapter.
- (6) If nSTATUS is monitored, follow the t<sub>ST2CK</sub> specification. If nSTATUS is not monitored, follow the t<sub>CF2CK</sub> specification.

### FPP Configuration Timing when DCLK-to-DATA [] > 1

Figure 13 shows the timing waveform for FPP configuration when using a MAX II device, MAX V device, or microprocessor as an external host. This waveform shows timing when the DCLK-to-DATA [] ratio is more than 1.

Table 51 lists the timing parameters for Stratix V devices for FPP configuration when the DCLK-to-DATA [ ] ratio is more than 1.

**Table 51. FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[ ] Ratio is >1 <sup>(1)</sup>**

Symbol	Parameter	Minimum	Maximum	Units
$t_{CF2CD}$	nCONFIG low to CONF_DONE low	—	600	ns
$t_{CF2ST0}$	nCONFIG low to nSTATUS low	—	600	ns
$t_{CFG}$	nCONFIG low pulse width	2	—	$\mu$ s
$t_{STATUS}$	nSTATUS low pulse width	268	1,506 <sup>(2)</sup>	$\mu$ s
$t_{CF2ST1}$	nCONFIG high to nSTATUS high	—	1,506 <sup>(2)</sup>	$\mu$ s
$t_{CF2CK}$ <sup>(5)</sup>	nCONFIG high to first rising edge on DCLK	1,506	—	$\mu$ s
$t_{ST2CK}$ <sup>(5)</sup>	nSTATUS high to first rising edge of DCLK	2	—	$\mu$ s
$t_{DSU}$	DATA [ ] setup time before rising edge on DCLK	5.5	—	ns
$t_{DH}$	DATA [ ] hold time after rising edge on DCLK	$N-1/f_{DCLK}$ <sup>(5)</sup>	—	s
$t_{CH}$	DCLK high time	$0.45 \times 1/f_{MAX}$	—	s
$t_{CL}$	DCLK low time	$0.45 \times 1/f_{MAX}$	—	s
$t_{CLK}$	DCLK period	$1/f_{MAX}$	—	s
$f_{MAX}$	DCLK frequency (FPP $\times 8/\times 16$ )	—	125	MHz
	DCLK frequency (FPP $\times 32$ )	—	100	MHz
$t_R$	Input rise time	—	40	ns
$t_F$	Input fall time	—	40	ns
$t_{CD2UM}$	CONF_DONE high to user mode <sup>(3)</sup>	175	437	$\mu$ s
$t_{CD2CU}$	CONF_DONE high to CLKUSR enabled	$4 \times$ maximum DCLK period	—	—
$t_{CD2UMC}$	CONF_DONE high to user mode with CLKUSR option on	$t_{CD2CU} + (8576 \times \text{CLKUSR period})$ <sup>(4)</sup>	—	—

**Notes to Table 51:**

- (1) Use these timing parameters when you use the decompression and design security features.
- (2) You can obtain this value if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.
- (3) The minimum and maximum numbers apply only if you use the internal oscillator as the clock source for initializing the device.
- (4) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the Initialization section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices” chapter.
- (5) N is the DCLK-to-DATA ratio and  $f_{DCLK}$  is the DCLK frequency the system is operating.
- (6) If nSTATUS is monitored, follow the  $t_{ST2CK}$  specification. If nSTATUS is not monitored, follow the  $t_{CF2CK}$  specification.

Table 54 lists the PS configuration timing parameters for Stratix V devices.

**Table 54. PS Timing Parameters for Stratix V Devices**

Symbol	Parameter	Minimum	Maximum	Units
$t_{CF2CD}$	nCONFIG low to CONF_DONE low	—	600	ns
$t_{CF2ST0}$	nCONFIG low to nSTATUS low	—	600	ns
$t_{CFG}$	nCONFIG low pulse width	2	—	$\mu$ s
$t_{STATUS}$	nSTATUS low pulse width	268	1,506 <sup>(1)</sup>	$\mu$ s
$t_{CF2ST1}$	nCONFIG high to nSTATUS high	—	1,506 <sup>(2)</sup>	$\mu$ s
$t_{CF2CK}$ <sup>(5)</sup>	nCONFIG high to first rising edge on DCLK	1,506	—	$\mu$ s
$t_{ST2CK}$ <sup>(5)</sup>	nSTATUS high to first rising edge of DCLK	2	—	$\mu$ s
$t_{DSU}$	DATA [] setup time before rising edge on DCLK	5.5	—	ns
$t_{DH}$	DATA [] hold time after rising edge on DCLK	0	—	ns
$t_{CH}$	DCLK high time	$0.45 \times 1/f_{MAX}$	—	s
$t_{CL}$	DCLK low time	$0.45 \times 1/f_{MAX}$	—	s
$t_{CLK}$	DCLK period	$1/f_{MAX}$	—	s
$f_{MAX}$	DCLK frequency	—	125	MHz
$t_{CD2UM}$	CONF_DONE high to user mode <sup>(3)</sup>	175	437	$\mu$ s
$t_{CD2CU}$	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	—	—
$t_{CD2UMC}$	CONF_DONE high to user mode with CLKUSR option on	$t_{CD2CU} + (8576 \times \text{CLKUSR period})$ <sup>(4)</sup>	—	—

**Notes to Table 54:**

- (1) This value is applicable if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.
- (2) This value is applicable if you do not delay configuration by externally holding the nSTATUS low.
- (3) The minimum and maximum numbers apply only if you choose the internal oscillator as the clock source for initializing the device.
- (4) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the “Initialization” section.
- (5) If nSTATUS is monitored, follow the  $t_{ST2CK}$  specification. If nSTATUS is not monitored, follow the  $t_{CF2CK}$  specification.

## Initialization

Table 55 lists the initialization clock source option, the applicable configuration schemes, and the maximum frequency.

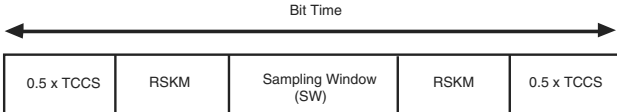
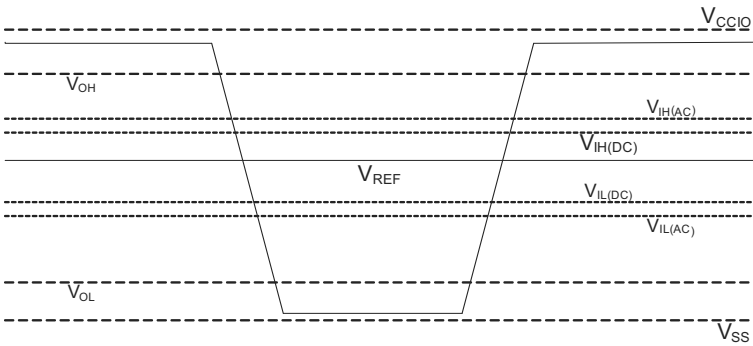
**Table 55. Initialization Clock Source Option and the Maximum Frequency**

Initialization Clock Source	Configuration Schemes	Maximum Frequency	Minimum Number of Clock Cycles <sup>(1)</sup>
Internal Oscillator	AS, PS, FPP	12.5 MHz	8576
CLKUSR	AS, PS, FPP <sup>(2)</sup>	125 MHz	
DCLK	PS, FPP	125 MHz	

**Notes to Table 55:**

- (1) The minimum number of clock cycles required for device initialization.
- (2) To enable CLKUSR as the initialization clock source, turn on the **Enable user-supplied start-up clock (CLKUSR)** option in the Quartus II software from the **General** panel of the **Device and Pin Options** dialog box.

Table 60. Glossary (Part 3 of 4)

Letter	Subject	Definitions
S	SW (sampling window)	<p>Timing Diagram—the period of time during which the data must be valid in order to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window, as shown:</p> 
	Single-ended voltage referenced I/O standard	<p>The JEDEC standard for <b>SSTL</b> and <b>HSTL</b> I/O defines both the AC and DC input signal values. The AC values indicate the voltage levels at which the receiver must meet its timing specifications. The DC values indicate the voltage levels at which the final logic state of the receiver is unambiguously defined. After the receiver input has crossed the AC value, the receiver changes to the new logic state.</p> <p>The new logic state is then maintained as long as the input stays beyond the DC threshold. This approach is intended to provide predictable receiver timing in the presence of input waveform ringing:</p> <p><i>Single-Ended Voltage Referenced I/O Standard</i></p> 
T	$t_c$	High-speed receiver and transmitter input and output clock period.
	TCCS (channel-to-channel-skew)	The timing difference between the fastest and slowest output edges, including $t_{CO}$ variation and clock skew, across channels driven by the same PLL. The clock is included in the TCCS measurement (refer to the <i>Timing Diagram</i> figure under <b>SW</b> in this table).
	$t_{DUTY}$	<p>High-speed I/O block—Duty cycle on the high-speed transmitter output clock.</p> <p><b>Timing Unit Interval (TUI)</b></p> <p>The timing budget allowed for skew, propagation delays, and the data sampling window. (TUI = <math>1/(\text{receiver input clock frequency multiplication factor}) = t_c/w</math>)</p>
	$t_{FALL}$	Signal high-to-low transition time (80-20%)
	$t_{INCCJ}$	Cycle-to-cycle jitter tolerance on the PLL clock input.
	$t_{OUTPJ\_IO}$	Period jitter on the general purpose I/O driven by a PLL.
	$t_{OUTPJ\_DC}$	Period jitter on the dedicated clock output driven by a PLL.
	$t_{RISE}$	Signal low-to-high transition time (20-80%)
U	—	—

**Table 60. Glossary (Part 4 of 4)**

Letter	Subject	Definitions
<b>V</b>	$V_{CM(DC)}$	DC common mode input voltage.
	$V_{ICM}$	Input common mode voltage—The common mode of the differential signal at the receiver.
	$V_{ID}$	Input differential voltage swing—The difference in voltage between the positive and complementary conductors of a differential transmission at the receiver.
	$V_{DIF(AC)}$	AC differential input voltage—Minimum AC input differential voltage required for switching.
	$V_{DIF(DC)}$	DC differential input voltage— Minimum DC input differential voltage required for switching.
	$V_{IH}$	Voltage input high—The minimum positive voltage applied to the input which is accepted by the device as a logic high.
	$V_{IH(AC)}$	High-level AC input voltage
	$V_{IH(DC)}$	High-level DC input voltage
	$V_{IL}$	Voltage input low—The maximum positive voltage applied to the input which is accepted by the device as a logic low.
	$V_{IL(AC)}$	Low-level AC input voltage
	$V_{IL(DC)}$	Low-level DC input voltage
	$V_{OCM}$	Output common mode voltage—The common mode of the differential signal at the transmitter.
	$V_{OD}$	Output differential voltage swing—The difference in voltage between the positive and complementary conductors of a differential transmission at the transmitter.
	$V_{SWING}$	Differential input voltage
	$V_X$	Input differential cross point voltage
	$V_{OX}$	Output differential cross point voltage
<b>W</b>	W	High-speed I/O block—clock boost factor
<b>X</b>	—	—
<b>Y</b>		
<b>Z</b>		